

IMMS

INSTITUT FÜR MIKROELEKTRONIK- UND
MECHATRONIK-SYSTEME GEMEINNÜTZIGE GMBH

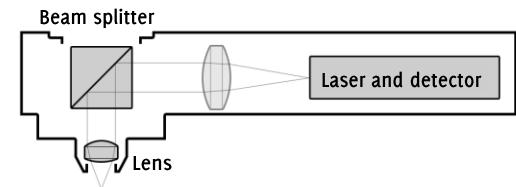
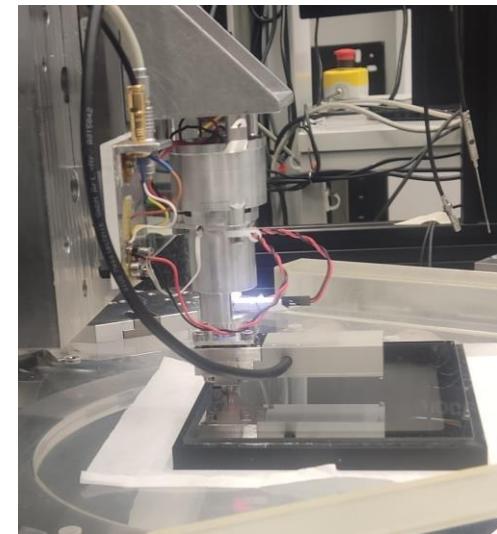
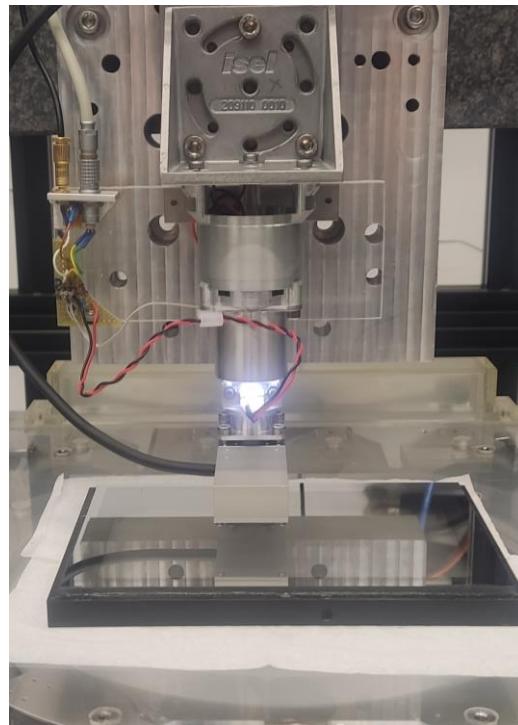
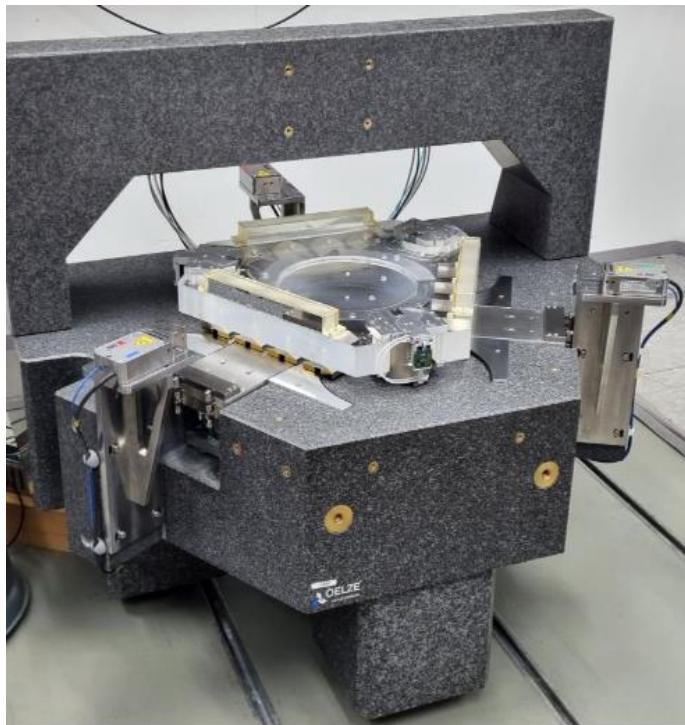
Unconventional, lateral measurements with laser focus sensor for nanopositioning stages

Ilmenau, 29.11.2023

Davi Anders Brasil

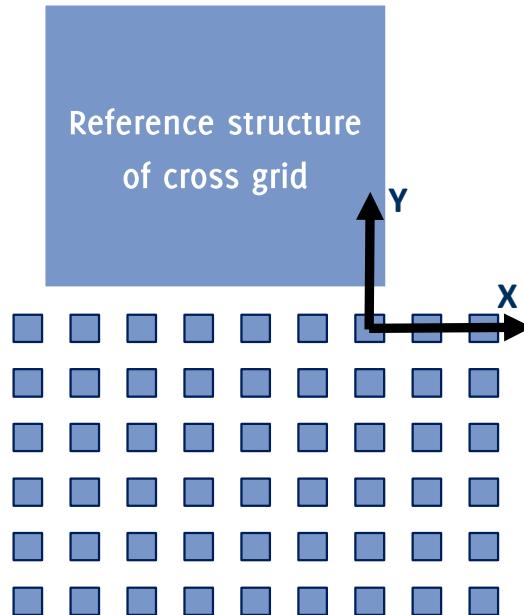


Laser focus sensor + 6DOF nanopositioning machine



Unconventional measurements – lateral

- Cross grid (chromium and glass)



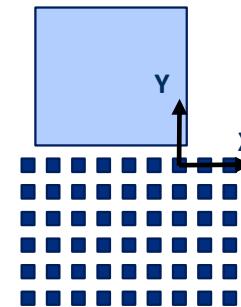
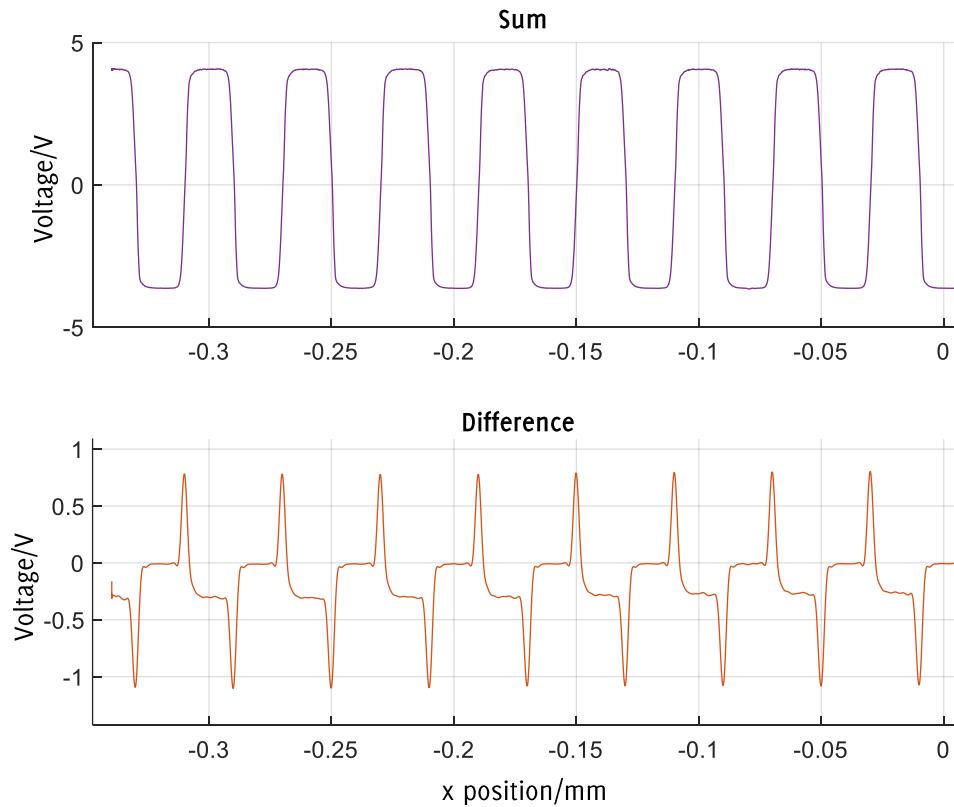
— Focus detection

— Length measurements

Non compensated results – system as it is



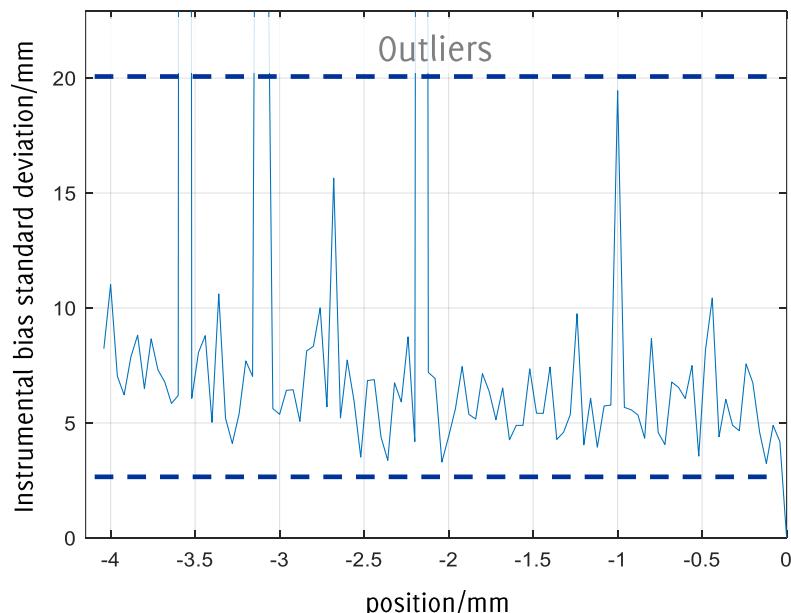
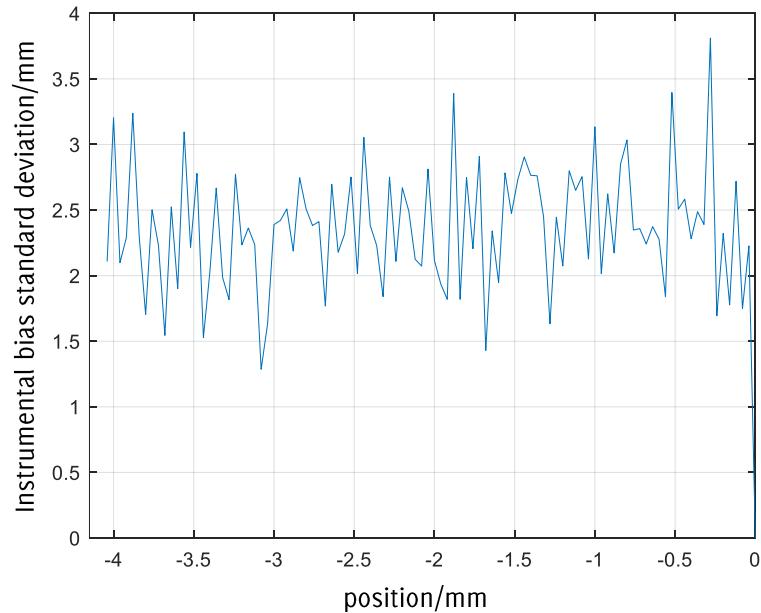
Laser focus sensor signals – lateral measurements



Standard deviation of the measurements in short and long term - 4mm range - worst case

– Good results (without compensation)

- SD measurements of measurements in the same day (less than 4 nm)
- SD measurements of measurements in different day (less than 20 nm)



An den nächsten Ideen für die Zukunft möchten wir gern gemeinsam mit Ihnen arbeiten!



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